

| <b>Form PTO-1449 (modified)</b><br>List of Patents and Publications<br>For Applicant's Information<br>Disclosure Statement<br>(Use several sheets if necessary) |   |   | ATTY. DKT. NO. 5589-04001    |                 | SERIAL NO. 10/679,857 |              |                               |
|---|---|---|------------------------------|-----------------|-----------------------|--------------|-------------------------------|
|   |   |   | APPLICANT: Stokowski et al.  |                 | GROUP: 2877           |              |                               |
|   |   |   | FILING DATE: October 6, 2003 |                 |                       |              |                               |
| <b>U.S. PATENT DOCUMENTS</b>  |   |   |                              |                 |                       |              |                               |
| EXAM.<br>INITIALS   | REF.<br>DES.  | DOCUMENT NUMBER   | DATE                         | NAME            | CLASS                 | SUB<br>CLASS | FILING DATE IF<br>APPROPRIATE |
| MS  | O I P E<br>DEC 27 2005<br>MS<br>PATENT & TRADEMARK OFFICE | 6466315   | 10/2002                      | Karpol et al.   |                       |              |                               |
| MS  |   | 6268093   | 07/2001                      | Kenan et al.    |                       |              |                               |
| MS  |   | 6184976   | 02/2001                      | Park et al.     |                       |              |                               |
| MS  |   | 6691052   | 02/2004                      | Maurer          |                       |              |                               |
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|   |   |   |                              |                 |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
| <b>U.S. PATENT APPLICATION DOCUMENTS</b>  |   |   |                              |                 |                       |              |                               |
| EXAM.<br>INITIALS   | REF.<br>DES.  | DOCUMENT NUMBER   | DATE                         | NAME            | CLASS                 | SUB<br>CLASS | FILING DATE IF<br>APPROPRIATE |
| MS  |   | 2003/0207475  | 11/2003                      | Nakasuji et al. |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
| <b>FOREIGN PATENT DOCUMENTS</b>   |   |   |                              |                 |                       |              |                               |
| EXAM.<br>INITIALS   | REF.<br>DES.  | DOCUMENT NUMBER   | DATE                         | COUNTRY         | CLASS                 | SUB<br>CLASS | TRANSLATION<br>YES/NO         |
|   |   |   |                              |                 |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
|   |   |   |                              |                 |                       |              |                               |
| <b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>   |   |   |                              |                 |                       |              |                               |
| MS  | E1  | Barty et al., "Aerial Image Microscopes for the inspection of defects in EUV masks," Proceedings of SPIE, Vol. 4889, 2002, pp. 1073-1084. |                              |                 |                       |              |                               |
| MS  | E2  | Yan et al., "Printability of Pellicle Defects in DUV 0.5 µm Lithography," SPIE Vol. 1604, 1991, pp. 106-117.                              |                              |                 |                       |              |                               |
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EXAMINER: /Michael Stafira/ DATE CONSIDERED: 05/19/2006

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.